Patent Assignment Abstract of Title

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PCT #: NONE　　　　　　　　　　　　　**Publication #:** NONE　　**Pub Dt:**
Inventors: Scott Williams, Alan Schachtely
Title: Custom rule system and method for expert systems

Assignment: 1

Reel/Frame: 011907/0654	**Received:** 06/22/2001	**Recorded:** 06/14/2001	**Mailed:** 08/29/2001

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Conveyance: ASSIGNMENT OF ASSIGNORS INTEREST (SEE DOCUMENT FOR DETAILS).

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